## Machine Learning and Deep Learning Applications for Anomaly and Fault Detection

Guest Editor:

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Deadline for manuscript submissions:
**closed (1 July 2023)**

### Message from the Guest Editor

The aim of this Special Issue is to collect recent developments in machine learning and deep learning algorithms, signal processing techniques, feature extraction, feature selection, and data science studies. It is expected that the studies will be application-oriented. The topics include, but are not limited to, the following:

- Deep Learning
- Machine Learning
- Object Detection
- Computer Vision
- Fault Diagnosis
- Anomaly Detection
- Machine Monitoring
- Fault Detection
- Signal Processing
- Predictive Maintenance
- Time-Series and Image-based detection

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# Special Issue

## Editor-in-Chief

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## Message from the Editor-in-Chief

Algorithms are the very core of Computer Science. The whole area has been considered from quite different perspectives, having led to the development of many sub-communities: Complexity theory (limitations), approximation or parameterized algorithms (types of problems), geometric algorithms (subject area), metaheuristics, algorithm engineering, medical imaging (applications), indicates the range of perspectives. Our journal welcomes submissions written from any of these perspectives, so that it may become a forum for exchange of ideas between the corresponding scientific subcommunities.

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